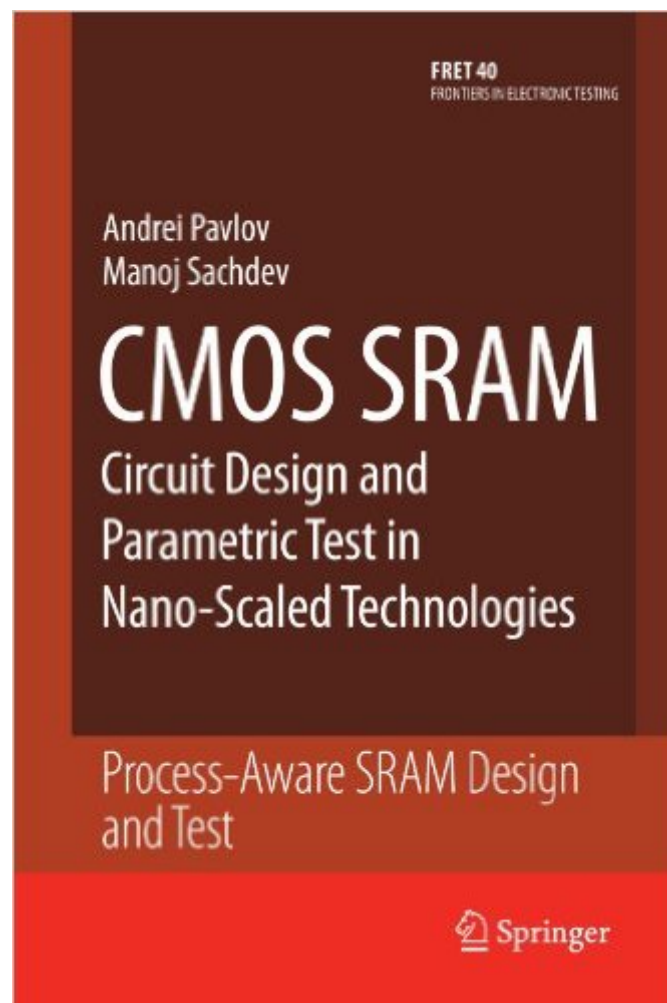


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CMOS SRAM Circuit Design And Parametric Test In Nano-Scaled Technologies: Process-Aware SRAM Design And Test (Frontiers In Electronic Testing)



Synopsis

The monograph will be dedicated to SRAM (memory) design and test issues in nano-scaled technologies by adapting the cell design and chip design considerations to the growing process variations with associated test issues. Purpose: provide process-aware solutions for SRAM design and test challenges.

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